

Notice of References Cited	Application/Control No. 10/040,917	Applicant(s)/Patent Under Reexamination KHESIN ET AL.	
	Examiner Kaj K Olsen	Art Unit 1753	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0 120 423 A1	10-1984	EPO	Hitachi, LTD.	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kimura et al, Principles and Development of a Thick-Film Zirconium Oxide Oxygen Sensor, pp. 101-120 from ACS Symposium Series 309, 1986.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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